

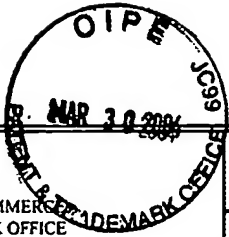


FORM PTO 1449 (modified)		ATTY DOCKET NO. 03500.017883		APPLICATION NO. 10/769,765		
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		APPLICANT HIROSHI AOTO ET AL.				
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		FILING DATE February 3, 2004		GROUP Unassigned 2861		
March 16, 2004						
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
mmf	3,946,398	03/1976	Kyser et al.	347	70	
	4,584,590	04/1986	Fischbeck et al.	347	69	
	5,265,315	11/1993	Hoisington et al.	29	25.35	
	6,653,211 B2	11/2003	Unno et al.	438	479	
	09/880,750 2002/0076875 A1	06/2002	Wasa et al.	029	025.30	pending
	10/071,095 2002/0140320 A1	10/2002	Unno et al.	310	324.000	issued 8-18-05
	6,927,084 2003/0196745 A1	08/2005 10/2003	Fukui et al.	438	021.000	
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
mmf	JP 53-12138	04/1978	Japan			*
mmf	JP 6-350154	12/1994	Japan			Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)						
mmf	*U.S. Patent No. 3,946,398 is a counterpart to JP 53-12138.					
EXAMINER	DATE CONSIDERED					

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicants.

DWP/tmc

Sheet 1 of 1



FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

March 30, 2004

ATTY DOCKET NO.
03500.017883APPLICATION NO.
10/769,765APPLICANT
HIROSHI AOTO ET AL.FILING DATE
February 3, 2004GROUP
Unassigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
mmt	4,825,227	04/1989	Fischbeck et al.	347	69	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
mmt	JP 55-11811	01/1980	Japan			Abstract
mmt	JP 62-22790	05/1987	Japan			Abstract*
mmt	JP 7-33089	04/1995	Japan			U.S. Counterpart*

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

mmt	*See text of IDS for explanation.
EXAMINER	DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicants.

Sheet 1 of 1

DWP/lmc



FORM PTO 1449 (modified)		ATTY DOCKET NO. 03500.017883		APPLICATION NO. 10/769,765	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		APPLICANT HIROSHI AOTO ET AL.			
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		FILING DATE February 3, 2004		GROUP 2853	
October 13, 2005					
U.S. PATENT DOCUMENTS					
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	FILING DATE IF APPROPRIATE
mm	5,265,315	11/1993	Hoisington et al.		
mm	4,584,590	04/1986	Fischbeck et al.		
FOREIGN PATENT DOCUMENTS					
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	TRANSLATION YES/NO/ OR ABSTRACT
mm	0 656 429 A	06/1995	Europe		Yes
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)					
mm	OGAWA et al., "Controlling The Crystal Orientations of Lead Titanate Thin Films", Japanese Journal of Applied Physics, Tokyo, Japan, vol. 30, no. 9B, September 1, 1991, pps. 2145-2148				
mm	LIN et al., "Epitaxial Growth of Pb(Zr _{0.2} Ti _{0.8})O ₃ On Si and its Nanoscale Piezoelectric Properties", Applied Physics Letters, American Institute of Physics, New York, USA, vol 78, no. 14, April 2, 2001, pps. 2034-2036				
EXAMINER	DATE CONSIDERED				

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicants.

DWPBLK/mls

Sheet 1 of 1